

IN THE CLAIMS

Please amend the claims as follows:

Claim 1 (Previously Presented): A high thermal conductive aluminum nitride sintered body having: a thermal conductivity of  $220 \text{ W/m} \cdot \text{K}$  or more; and a three point bending strength of  $250 \text{ MPa}$  or more; wherein a ratio ( $I_{\text{Al}_2\text{Y}_4\text{O}_9}/I_{\text{AlN}}$ ) of X-ray diffraction intensity ( $I_{\text{Al}_2\text{Y}_4\text{O}_9}$ ) of  $\text{Al}_2\text{Y}_4\text{O}_9$  (201 plane) with respect to X-ray diffraction intensity ( $I_{\text{AlN}}$ ) of aluminum nitride (101 plane) is 0.002 to 0.03.

Claim 2 (Previously Presented): A high thermal conductive aluminum nitride sintered body according to Claim 1, wherein a ratio ( $I_{\text{Y}_2\text{O}_3}/I_{\text{AlN}}$ ) of X-ray diffraction intensity ( $I_{\text{Y}_2\text{O}_3}$ ) of  $\text{Y}_2\text{O}_3$  (222 plane) with respect to X-ray diffraction intensity ( $I_{\text{AlN}}$ ) of AlN (101 plane) is 0.002 to 0.06.

Claim 3 (Previously Presented): A high thermal conductive aluminum nitride sintered body having: a thermal conductivity of  $200 \text{ W/m} \cdot \text{K}$  or more; and a three point bending strength of  $250 \text{ MPa}$  or more; wherein a ratio ( $I_{\text{Al}_2\text{Y}_4\text{O}_9}/I_{\text{AlN}}$ ) of X-ray diffraction intensity ( $I_{\text{Al}_2\text{Y}_4\text{O}_9}$ ) of  $\text{Al}_2\text{Y}_4\text{O}_9$  ~~aluminum nitride~~ (201 plane) with respect to X-ray diffraction intensity ( $I_{\text{AlN}}$ ) of AlN (101 plane) is 0.002 to 0.06, and a ratio ( $I_{\text{Y}_2\text{O}_3}/I_{\text{AlN}}$ ) of X-ray diffraction intensity ( $I_{\text{Y}_2\text{O}_3}$ ) of  $\text{Y}_2\text{O}_3$  (222 plane) with respect to X-ray diffraction intensity ( $I_{\text{AlN}}$ ) of AlN (101 plane) is 0.008 to 0.06.

Claim 4 (Previously Presented): A high thermal conductive aluminum nitride sintered body according to Claim 1, wherein said aluminum nitride sintered body contains 0.14 – 1.5 mass% of Y element and 0.05 – 0.5 mass% of oxygen, a mass ratio (O/Y) of oxygen (O) with respect to Y element is 0.5 or less, an average diameter of aluminum nitride crystal grains is 4  $\mu\text{m}$  or more, a number of crystal grains existing in arbitrary crystal structure area of  $100\mu\text{m}\times 100\mu\text{m}$  is 200 or less, a maximum diameter of grain boundary phase is 0.5  $\mu\text{m}$  or less.

Claim 5 (Currently Amended): A high thermal conductive aluminum nitride sintered body according to Claim 1, wherein said aluminum nitride sintered body contains 0.14 – 1.5 mass% of Y element and 0.05 – 0.5 mass% of oxygen, a mass ratio (O/Y) of oxygen (O) with respect to Y element is 0.6 or less, an average diameter of aluminum nitride crystal grains is ~~[[4]]~~ 6  $\mu\text{m}$  or more, a number of crystal grains existing in arbitrary crystal structure area of  $100\mu\text{m}\times 100\mu\text{m}$  is 150 or less, a maximum diameter of grain boundary phase is 0.5  $\mu\text{m}$  or less.